Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/886,741	CHAN ET AL.	
Examiner	Art Unit	_
Chris C. Chu	2815	

	SEARCHED		
Class	Subclass	Date	Examiner
257	796 & 685	6/17/2005	C.C.

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	I		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	6/17/2005	C.C.
		,
-		